



STGW45HF60WD

45 A, 600 V ultra fast IGBT

Preliminary data

Features

- Improved E_{off} at elevated temperature
- Low C_{RES} / C_{IES} ratio (no cross-conduction susceptibility)
- Ultra fast soft recovery antiparallel diode

Applications

- Welding
- High frequency converters
- Power factor correction

Description

The "HF" series is based on a new planar technology concept to yield an IGBT with tighter variation of switching energy (E_{off}) versus temperature. Suffix "W" denotes a subset of products tailored to high switching frequency operation over 100 kHz.

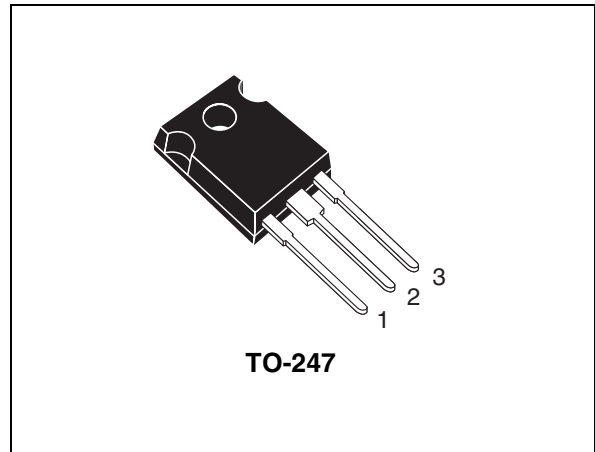


Figure 1. Internal schematic diagram

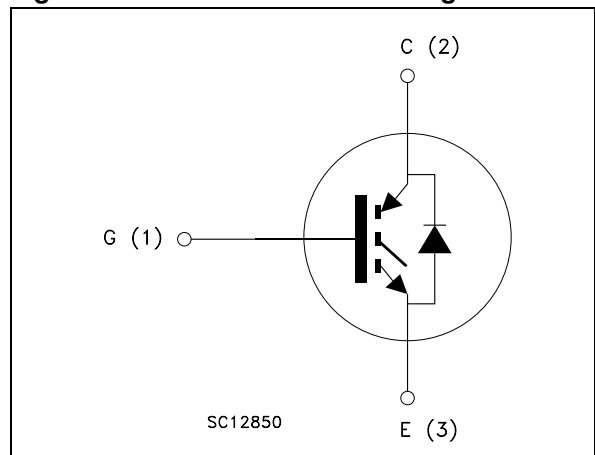


Table 1. Device summary

Order code	Marking	Package	Packaging
STGW45HF60WD	GW45HF60WD	TO-247	Tube

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$)	600	V
$I_C^{(1)}$	Continuous collector current at $T_C = 25\text{ °C}$	70	A
$I_C^{(1)}$	Continuous collector current at $T_C = 100\text{ °C}$	45	A
$I_{CP}^{(2)}$	Collector current (pulsed)	TBD	A
$I_{CL}^{(3)}$	Turn-off latching current	TBD	A
V_{GE}	Gate-emitter voltage	± 20	V
I_F	Diode RMS forward current at $T_C = 25\text{ °C}$	30	A
I_{FSM}	Surge not repetitive forward current $t_p = 10\text{ ms}$ sinusoidal	120	A
P_{TOT}	Total dissipation at $T_C = 25\text{ °C}$	250	W
T_{stg}	Storage temperature	- 55 to 150	°C
T_j	Operating junction temperature		

1. Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{j(max)} - T_C}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_C(T_C))}$$

2. Pulse width limited by maximum junction temperature and turn-off within RBSOA

3. $V_{CLAMP} = 80\% (V_{CES})$, $V_{GE} = 15\text{ V}$, $R_G = 10\text{ }\Omega$, $T_J = 150\text{ °C}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case IGBT	0.5	°C/W
	Thermal resistance junction-case diode	1.5	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient	50	°C/W

2 Electrical characteristics

($T_J = 25\text{ °C}$ unless otherwise specified)

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage ($V_{GE} = 0$)	$I_C = 1\text{ mA}$	600			V
$V_{CE(sat)}$	Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}$, $I_C = 30\text{ A}$ $V_{GE} = 15\text{ V}$, $I_C = 30\text{ A}$, $T_J = 125\text{ °C}$		1.9 TBD	2.5	V V
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}$, $I_C = 1\text{ mA}$	3.75		5.75	V
I_{CES}	Collector cut-off current ($V_{GE} = 0$)	$V_{CE} = 600\text{ V}$ $V_{CE} = 600\text{ V}$, $T_J = 125\text{ °C}$			500 5	μA mA
I_{GES}	Gate-emitter leakage current ($V_{CE} = 0$)	$V_{GE} = \pm 20\text{ V}$			± 100	nA
g_{fs}	Forward transconductance	$V_{CE} = 15\text{ V}$, $I_C = 30\text{ A}$		TBD		S

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GE} = 0$	-	TBD	-	pF
C_{oes}	Output capacitance			TBD		pF
C_{res}	Reverse transfer capacitance			TBD		pF
Q_g	Total gate charge	$V_{CE} = 390\text{ V}$, $I_C = 30\text{ A}$, $V_{GE} = 15\text{ V}$, Figure 3	-	TBD	-	nC
Q_{ge}	Gate-emitter charge			TBD		nC
Q_{gc}	Gate-collector charge			TBD		nC

Table 6. Switching on/off (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$		TBD		ns
t_r	Current rise time	$R_G = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$,	-	TBD	-	ns
$(di/dt)_{on}$	Turn-on current slope	<i>Figure 2</i>		TBD		A/ μ s
$t_{d(on)}$	Turn-on delay time	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$		TBD		ns
t_r	Current rise time	$R_G = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$,	-	TBD	-	ns
$(di/dt)_{on}$	Turn-on current slope	$T_J = 125\text{ }^\circ\text{C}$ <i>Figure 2</i>		TBD		A/ μ s
$t_r(V_{off})$	Off voltage rise time	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$,		TBD		ns
$t_{d(off)}$	Turn-off delay time	$R_{GE} = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$	-	TBD	-	ns
t_f	Current fall time	<i>Figure 2</i>		TBD		ns
$t_r(V_{off})$	Off voltage rise time	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$,		TBD		ns
$t_{d(off)}$	Turn-off delay time	$R_{GE} = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$,	-	TBD	-	ns
t_f	Current fall time	$T_J = 125\text{ }^\circ\text{C}$ <i>Figure 2</i>		TBD		ns

Table 7. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{on}^{(1)}$	Turn-on switching losses	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$		300		μ J
E_{off}	Turn-off switching losses	$R_G = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$,	-	330		μ J
E_{ts}	Total switching losses	<i>Figure 4</i>		630		μ J
$E_{on}^{(1)}$	Turn-on switching losses	$V_{CC} = 390\text{ V}$, $I_C = 30\text{ A}$		550		μ J
E_{off}	Turn-off switching losses	$R_G = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$,	-	550	800	μ J
E_{ts}	Total switching losses	$T_J = 125\text{ }^\circ\text{C}$ <i>Figure 4</i>		1100		μ J

1. E_{on} is the turn-on losses when a typical diode is used in the test circuit in *Figure 4*. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature ($25\text{ }^\circ\text{C}$ and $125\text{ }^\circ\text{C}$). E_{on} include diode recovery energy.

Table 8. Collector-emitter diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_F	Forward on-voltage	$I_F = 30\text{ A}$ $I_F = 30\text{ A}$, $T_J = 125\text{ }^\circ\text{C}$	-	1.6 1.4	-	V V
t_{rr}	Reverse recovery time	$I_F = 30\text{ A}$, $V_R = 50\text{ V}$,		45		ns
Q_{rr}	Reverse recovery charge	$di/dt = 100\text{ A}/\mu\text{s}$	-	56	-	nC
I_{rrm}	Reverse recovery current	(see <i>Figure 5</i>)		2.55		A
t_{rr}	Reverse recovery time	$I_F = 30\text{ A}$, $V_R = 50\text{ V}$,		100		ns
Q_{rr}	Reverse recovery charge	$di/dt = 100\text{ A}/\mu\text{s}$	-	290	-	nC
I_{rrm}	Reverse recovery current	$T_J = 125\text{ }^\circ\text{C}$, (see <i>Figure 5</i>)		5.8		A

3 Test circuits

Figure 2. Test circuit for inductive load switching

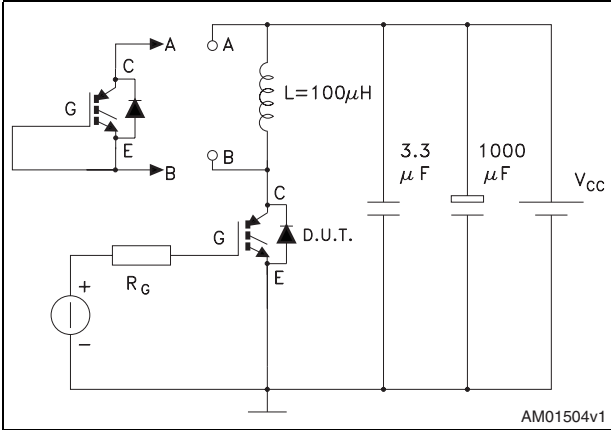


Figure 3. Gate charge test circuit

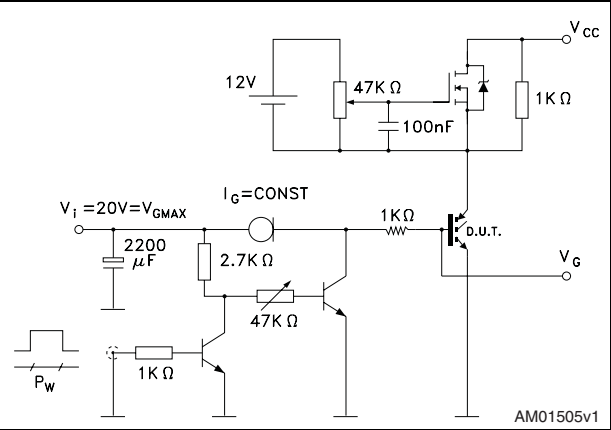


Figure 4. Switching waveform

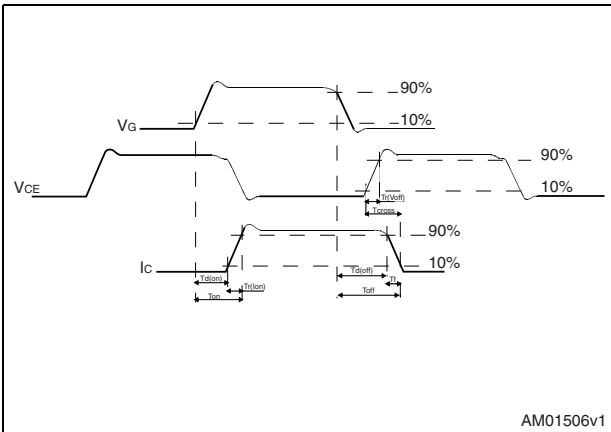
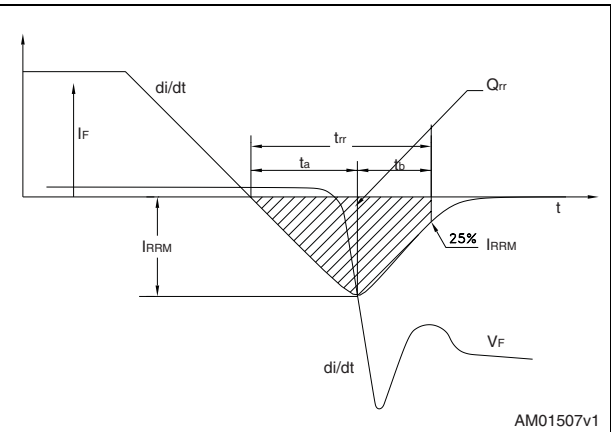


Figure 5. Diode recovery time waveform

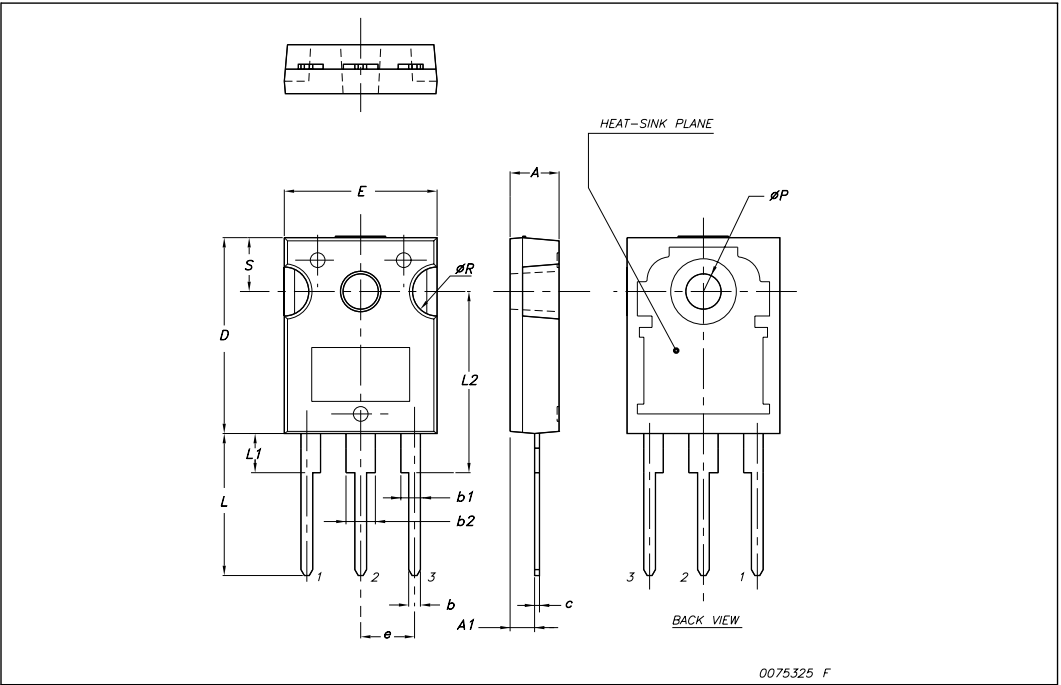


4 **Package mechanical data**

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

TO-247 Mechanical data

Dim.	mm.		
	Min.	Typ	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
øP	3.55		3.65
øR	4.50		5.50
S		5.50	



5 Revision history

Table 9. Document revision history

Date	Revision	Changes
16-Apr-2009	1	Initial release.
04-Aug-2009	2	– Modified I_C value on Test conditions Table 4 – Modified R_G value on Test conditions Table 6 and Table 7

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